

### Applications

- Microwave Reference
- RFICs
- T/R Modules

### Overview

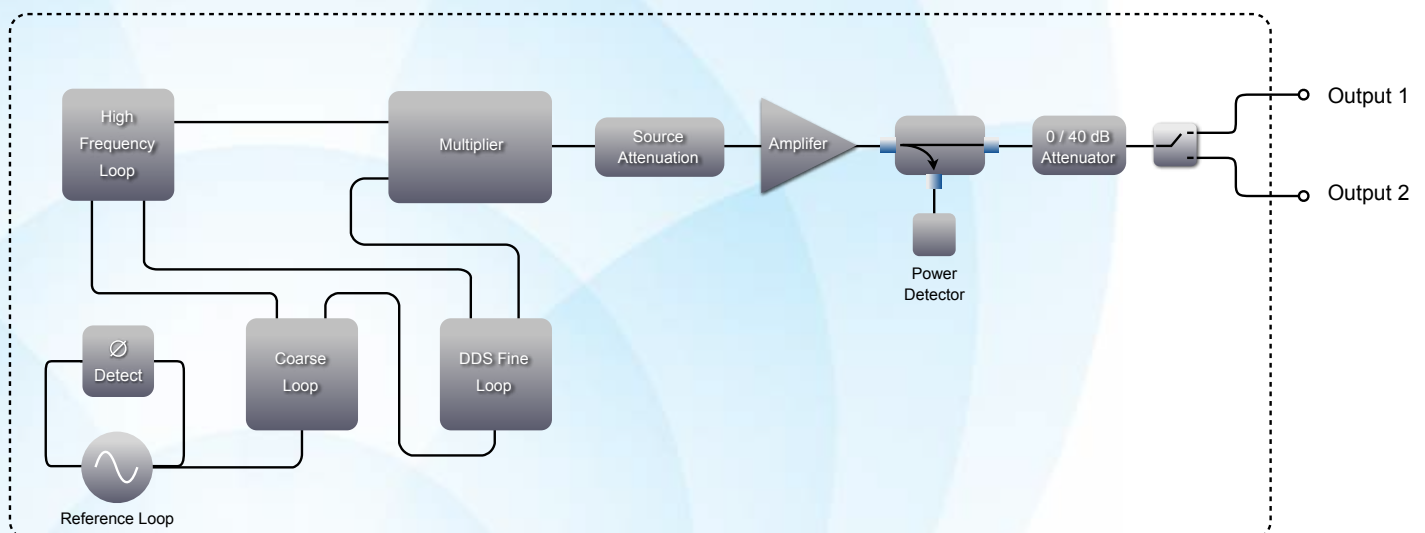
The RI8586 provides ultra-low phase noise, continuous wave signal generation from 25 MHz to 24 GHz. The microwave source functions as a stand-alone instrument as well as incorporating RI's SyRF Core technology to support seamless system integration with Cassini receiver and test set instruments for vector-calibrated VNA measurements. Designed for high-volume production test applications, the RI8586 features fast frequency switching, multi-port signal routing, and vector calibration to deliver high-fidelity power and phase control.



### Key Features

- *Wideband Frequency Range from 25 MHz to 24 GHz*
- *Ultra-Low Phase Noise (-120 dB/Hz 100 kHz offset @10 GHz)*
- *Wide Dynamic Range -80 dBm to +15 dBm*
- *Microsecond Frequency Switching <0.5 ms (typical)*

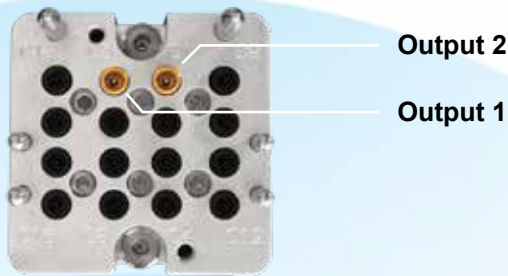
### Block Diagram



## Performance

Frequency Range	25 MHz to 24 GHz
Power Range	-80 dBm to +15 dBm
Phase Noise	-120 dB/Hz (@10GHz)

## Inputs/Outputs



## Cassini Test Systems

A versatile, high-speed, automated test solution for analog, mixed-signal, RF, and millimeter-wave devices.

Cassini provides a modular base architecture that is fully configurable via Test Instrument Modules (TIMs) to meet the needs of any IC, wafer, or module test requirement.

Each TIM contains internally-cooled, RF-shielded measurement instrumentation, signal distribution, and blind mate interfacing to provide targeted test resources and integrate to build up a complete production test platform.

Combined with Roos Instruments' integrated test software, Cassini can be configured to any application for maximum performance, true low cost of test, and the industry's fastest test times.

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